

60V N-Channel Enhancement Mode MOSFET

Description

The AP50N06Y uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS}=60V I_D =50A

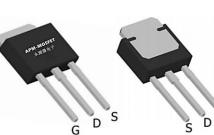
 $R_{DS(ON)} < 20m\Omega @ V_{GS}=10V$ (Type: 14m Ω)

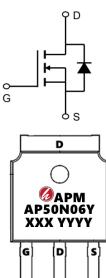
Application

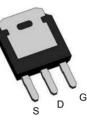
Battery protection

Load switch

Uninterruptible power supply







Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP50N06Y	TO-251L-3L	AP50N06Y XXXX YYYY	4000
AP50N06Y	TO-251S-3L	AP50N06Y XXXX YYYY	4000

G

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Parameter Rating	
VDS	Drain-Source Voltage	Drain-Source Voltage 60	
VGS	Gate-Source Voltage	±20	V
I₀@Tc=25℃	$_{C=25^{\circ}C}$ Continuous Drain Current, V _{GS} @ 10V ¹ 50		А
I₀@Tc=100°C	Continuous Drain Current, V _{GS} @ 10V ¹	25	A
IDM	Pulsed Drain Current ²	90	А
EAS	Single Pulse Avalanche Energy ³	39.2	mJ
IAS	Avalanche Current	28	А
P _D @T _C =25℃	Total Power Dissipation ⁴	45	W
PD@TA=25°C	Total Power Dissipation ⁴	2	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-Ambient ¹	62	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	2.8	°C/W

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60	65		V	
∆BVDSS/∆TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA		0.057		V/°C	
		V _{GS} =10V , I _D =20A		14	20		
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =10A		18	25	mΩ	
VGS(th)	Gate Threshold Voltage		1.2	1.8	2.5	V	
$\bigtriangleup V_{\text{GS(th)}}$	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =250uA		-5.68		mV/°C	
	Drain Course Lookana Current	V _{DS} =48V , V _{GS} =0V , T _J =25°C			1	uA	
IDSS	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =55°C			5		
IGSS	Gate-Source Leakage Current	V_{GS} =±20V , V_{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =5V , I _D =15A		45		S	
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7		Ω	
Qg	Total Gate Charge (4.5V)			19.3		nC	
Q _{gs}	Gate-Source Charge	$V_{\text{DS}}\text{=}48V$, $V_{\text{GS}}\text{=}4.5V$, $I_{\text{D}}\text{=}15A$		7.1			
Q_gd	Gate-Drain Charge			7.6			
Td(on)	Turn-On Delay Time			7.2			
Tr	Rise Time	V _{DD} =30V , V _{GS} =10V , R _G =3.3□,		50		ns	
Td(off)	Turn-Off Delay Time	I _D =15A		36.4		115	
T _f	Fall Time			7.6			
Ciss	Input Capacitance			2423			
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		145		pF	
Crss	Reverse Transfer Capacitance			97		1	
ls	Continuous Source Current ^{1,5}				35	Α	
ISM	Pulsed Source Current ^{2,5}	$V_G=V_D=0V$, Force Current			80	Α	
VSD	Diode Forward Voltage ²	V _{GS} =0V , Is=A , Tյ=25℃			1	V	
t _{rr}	Reverse Recovery Time			16.3		nS	
Qrr	Reverse Recovery Charge	IF=15A,dI/dt=100A/µs ,Tյ=25℃		11		nC	

Note :

1、 he data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

 $2\,{\scriptstyle \smallsetminus}\,$ he data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%$

3、he EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=28A

4、 he power dissipation is limited by 150°C junction temperature

 5_{v} he data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

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Typical Characteristics

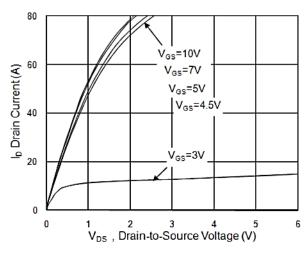


Fig.1 Typical Output Characteristics

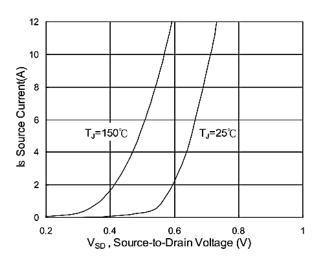


Fig.3 Forward Characteristics of Reverse

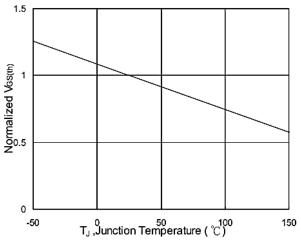


Fig.5 Normalized V_{GS} v.s T_J

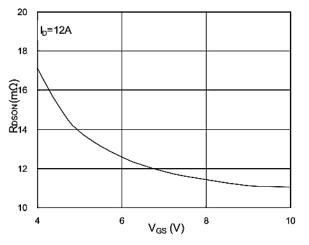


Fig.2 On-Resistance v.s Gate-Source

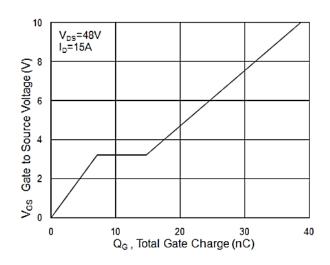


Fig.4 Gate-Charge Characteristics

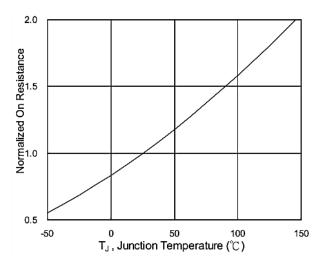


Fig.6 Normalized R_{DSON} v.s T_J



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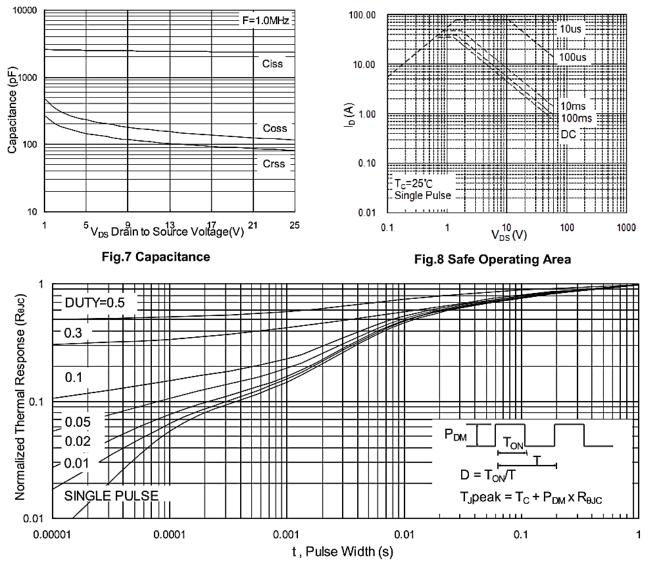


Fig.9 Normalized Maximum Transient Thermal Impedance

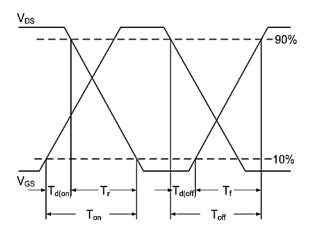


Fig.10 Switching Time Waveform

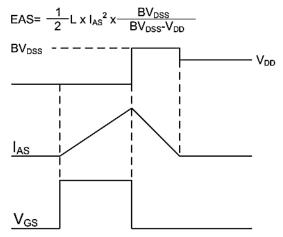


Fig.11 Unclamped Inductive Switching Waveform



AP50N06Y

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Package Mechanical Data-TO-251L-3L

TO-251

	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max
A	2.20		2.40	0.086		0.095
A2	0.90		1.20	0.035		0.047
в	0.55		0.65	0.022		0.026
B2	5.10		5.40	0.200		0.213
B3	0.76		0.85	0.030		0.033
С	0.45		0.62	0.018		0.024
C2	0.48		0.62	0.019		0.024
D	6.00		6.20	0.236		0.244
E	6.40		6.70	0.252		0.264
G		2.30			0.091	
н	16.0		17.0	0.630]	0.669
L	8.90		9.40	0.350		0.370
L1	1.80		1.90	0.071		0.075
L2	1.37		1.50	0.054		0.059
V1		4°	1		4°	

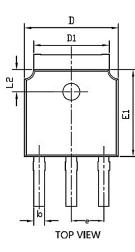
Package Information -TO-251

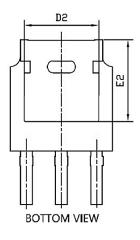
OUTLINE	TUBE	INNER BOX	PER CARTON
	(PCS)	(PCS)	(PCS)
TUBE	80	4,000	32,000

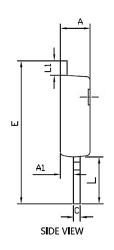


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Package Mechanical Data-TO-251S-3L







	Common				
Symbol	mm				
	Mim	Nom	Max		
A	2.2	2.3	2.4		
A1	0.9	1.0	1.1		
b	0.66	0.76	0.86		
С	0.46	0.52	0.58		
D	6.50	6.6	6.7		
D1	5.15	5.3	5.45		
D2	4.6	4.8	4.95		
E	10.4		11.5		
E1	6.0	6.1	6.2		
E2	5.400REF				
е	2.286BSC				
L	3.5	4.0	4.3		
L1	0.9		1.27		
L2	1.4		1.9		

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Edition	Date	Change
Rve1.0	2020/1/31	Initial release
Rve1.1	2021/8/35	New profile

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